

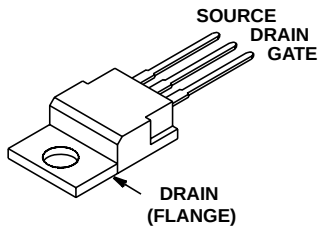
43A, 150V, 0.042 Ohm, N-Channel,
UltraFET Power MOSFET



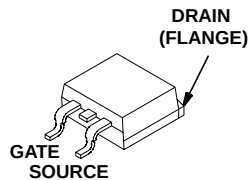
Packaging

JEDEC TO-220AB

JEDEC TO-263AB

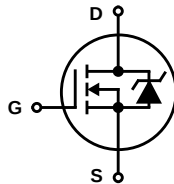


HUF75842P3



HUF75842S3S

Symbol



Features

- Ultra Low On-Resistance
 - $r_{DS(ON)} = 0.042\Omega$, $V_{GS} = 10V$
- Simulation Models
 - Temperature Compensated PSPICE® and SABER™ Electrical Models
 - Spice and SABER Thermal Impedance Models
 - www.intersil.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve

Ordering Information

PART NUMBER	PACKAGE	BRAND
HUF75842P3	TO-220AB	75842P
HUF75842S3S	TO-263AB	75842S

NOTE: When ordering, use the entire part number. Add the suffix T to obtain the variant in tape and reel, e.g., HUF75842S3ST.

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

	HUF75842P3	UNITS
Drain to Source Voltage (Note 1)	150	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1)	150	V
Gate to Source Voltage	± 20	V
Drain Current		
Continuous ($T_C = 25^\circ\text{C}$, $V_{GS} = 10V$) (Figure 2)	43	A
Continuous ($T_C = 100^\circ\text{C}$, $V_{GS} = 10V$) (Figure 2)	30	A
Pulsed Drain Current	Figure 4	
Pulsed Avalanche Rating	Figures 6, 14, 15	
Power Dissipation	230	W
Derate Above 25°C	1.53	W/ $^\circ\text{C}$
Operating and Storage Temperature	-55 to 175	$^\circ\text{C}$
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s.	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief TB334.	260	$^\circ\text{C}$

NOTES:

1. $T_J = 25^\circ\text{C}$ to 150°C .

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

HUF75842P3, HUF75842S3SS

Electrical Specifications $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
OFF STATE SPECIFICATIONS							
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} = 0V (Figure 11)	150	-	-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 140V, V _{GS} = 0V	-	-	1	μA	
		V _{DS} = 135V, V _{GS} = 0V, T _C = 150 ⁰ C	-	-	250	μA	
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V	-	-	±100	nA	
ON STATE SPECIFICATIONS							
Gate to Source Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250μA (Figure 10)	2	-	4	V	
Drain to Source On Resistance	r _{DS(ON)}	I _D = 43A, V _{GS} = 10V (Figure 9)	-	0.035	0.042	Ω	
THERMAL SPECIFICATIONS							
Thermal Resistance Junction to Case	R _{θJC}	TO-220	-	-	0.65	°C/W	
Thermal Resistance Junction to Ambient	R _{θJA}		-	-	62	°C/W	
SWITCHING SPECIFICATIONS (V _{GS} = 10V)							
Turn-On Time	t _{ON}	V _{DD} = 75V, I _D = 43A V _{GS} = 10V, R _{GS} = 3.9Ω (Figures 18, 19)	-	-	100	ns	
Turn-On Delay Time	t _{d(ON)}		-	13	-	ns	
Rise Time	t _r		-	53	-	ns	
Turn-Off Delay Time	t _{d(OFF)}		-	47	-	ns	
Fall Time	t _f		-	34	-	ns	
Turn-Off Time	t _{OFF}		-	-	120	ns	
GATE CHARGE SPECIFICATIONS							
Total Gate Charge	Q _{g(TOT)}	V _{GS} = 0V to 20V	V _{DD} = 75V, I _D = 43A, I _{g(REF)} = 1.0mA (Figures 13, 16, 17)	-	144	175	nC
Gate Charge at 10V	Q _{g(10)}	V _{GS} = 0V to 10V		-	77	90	nC
Threshold Gate Charge	Q _{g(TH)}	V _{GS} = 0V to 2V		-	5.6	6.7	nC
Gate to Source Gate Charge	Q _{gs}			-	12	-	nC
Gate to Drain "Miller" Charge	Q _{gd}			-	30	-	nC
CAPACITANCE SPECIFICATIONS							
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz (Figure 12)	-	2730	-	pF	
Output Capacitance	C _{OSS}		-	660	-	pF	
Reverse Transfer Capacitance	C _{RSS}		-	230	-	pF	

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V_{SD}	$I_{SD} = 43\text{A}$	-	-	1.25	V
		$I_{SD} = 22\text{A}$	-	-	1.00	V
Reverse Recovery Time	t_{rr}	$I_{SD} = 43\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	190	ns
Reverse Recovered Charge	Q_{RR}	$I_{SD} = 43\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	1.08	μC

Typical Performance Curves

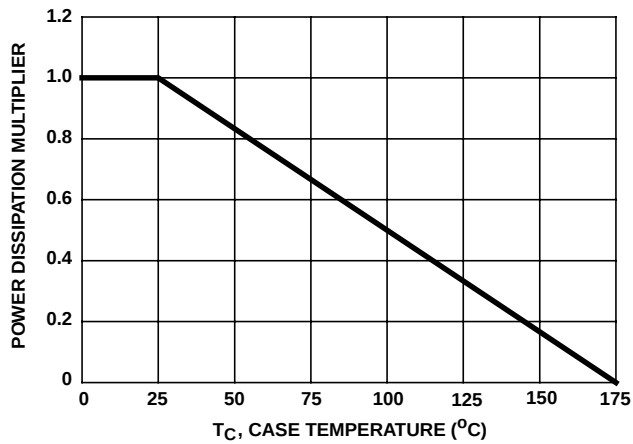


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

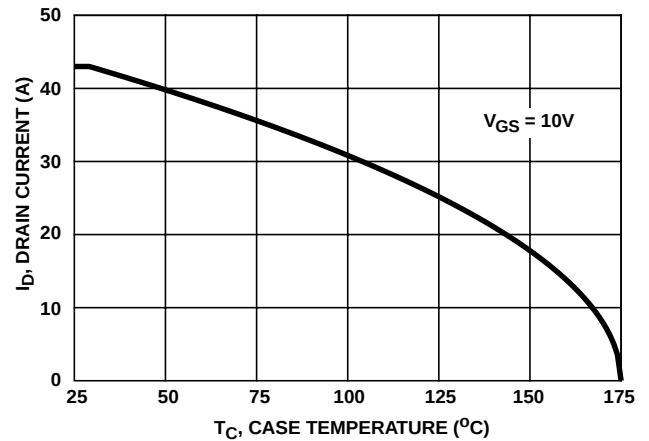


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

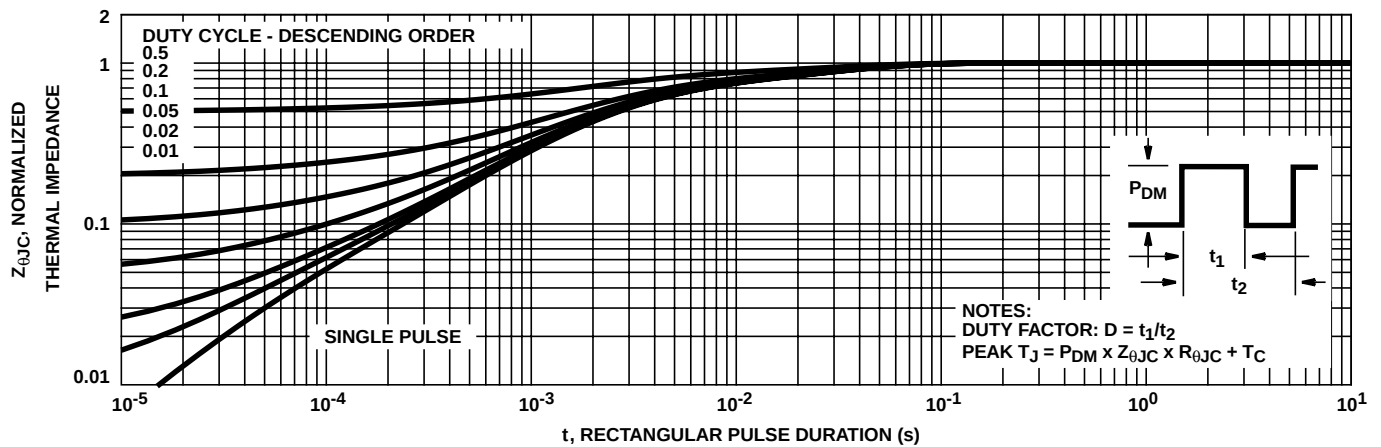


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

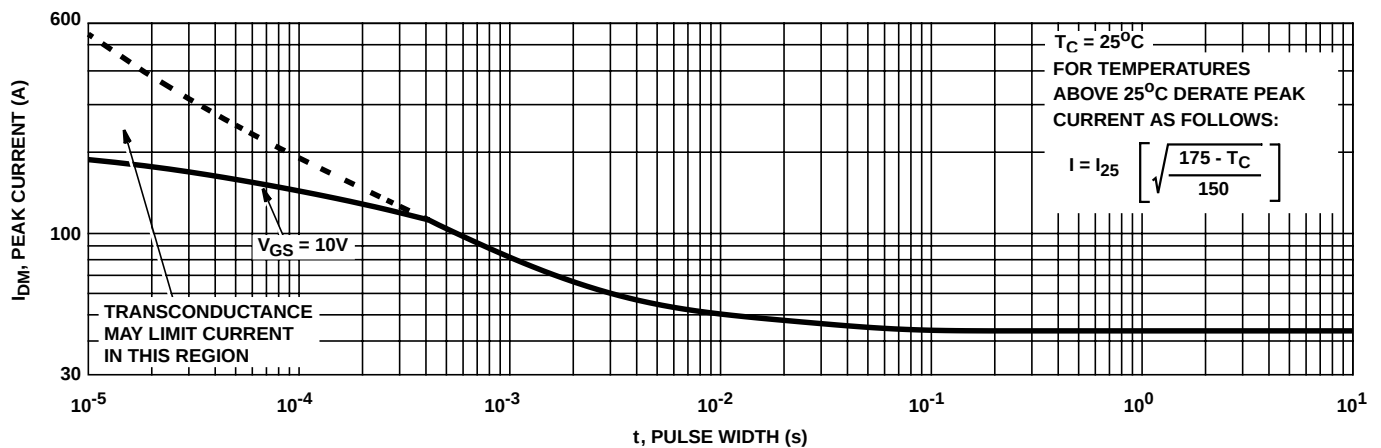


FIGURE 4. PEAK CURRENT CAPABILITY

Typical Performance Curves (Continued)

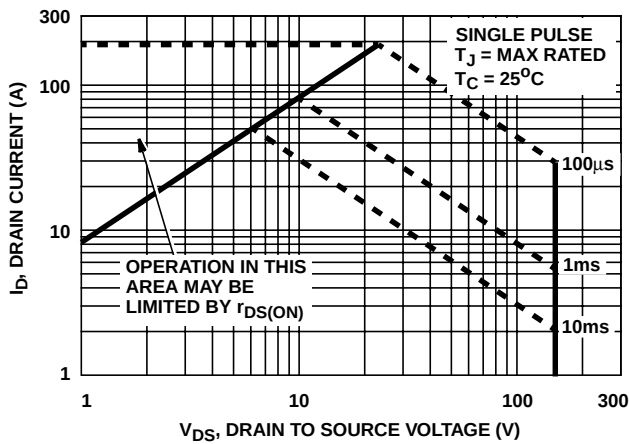
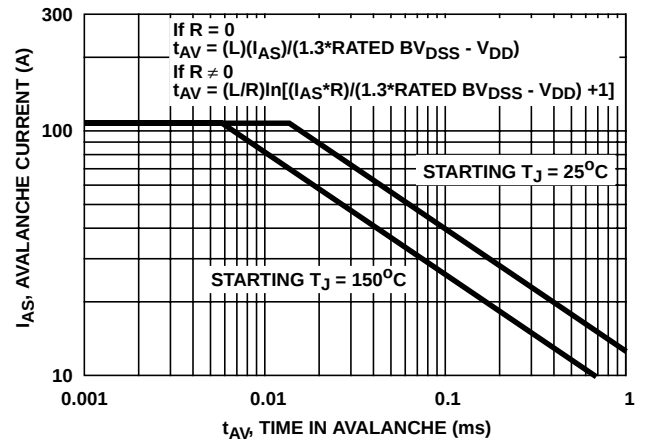


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA



NOTE: Refer to Intersil Application Notes AN9321 and AN9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

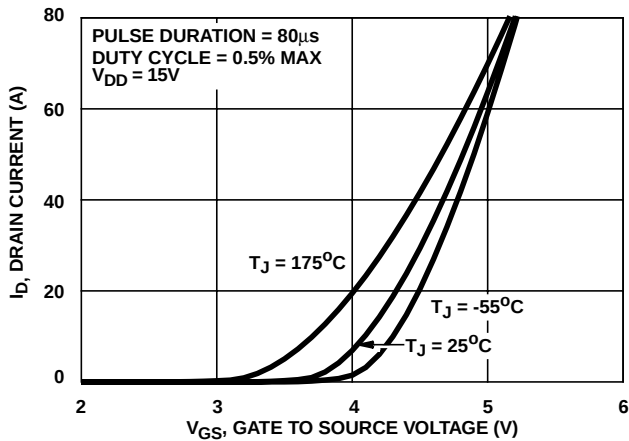


FIGURE 7. TRANSFER CHARACTERISTICS

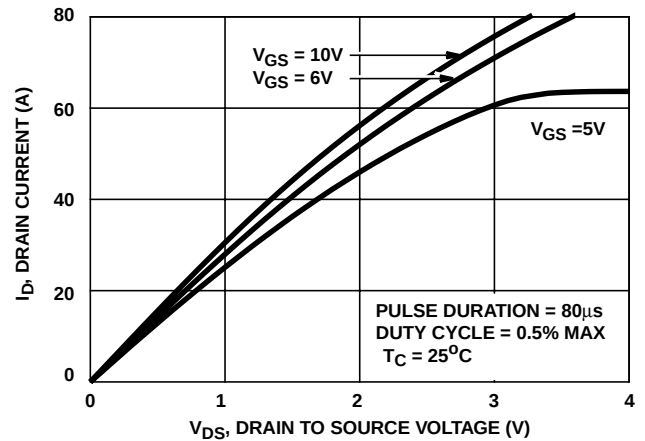


FIGURE 8. SATURATION CHARACTERISTICS

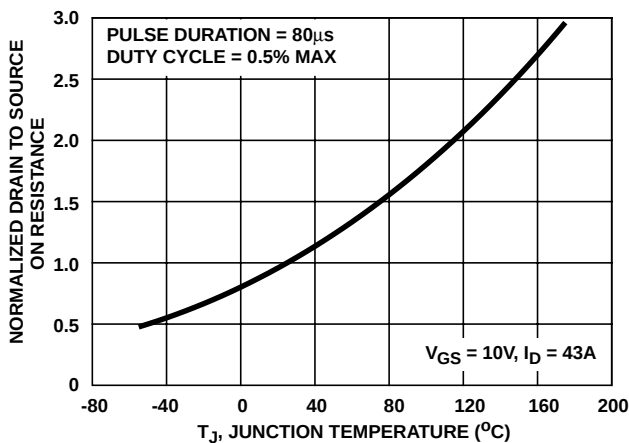


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

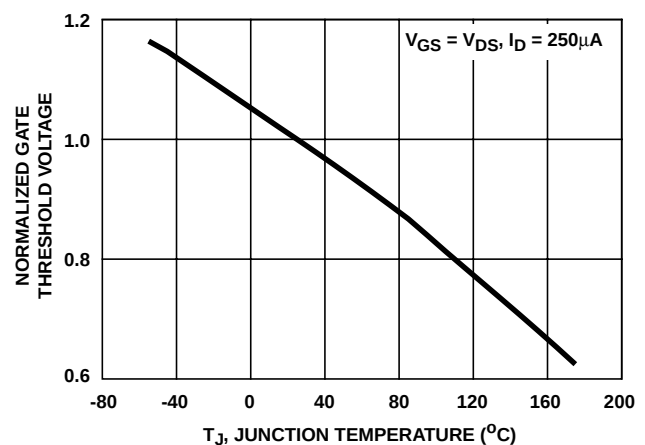


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves (Continued)

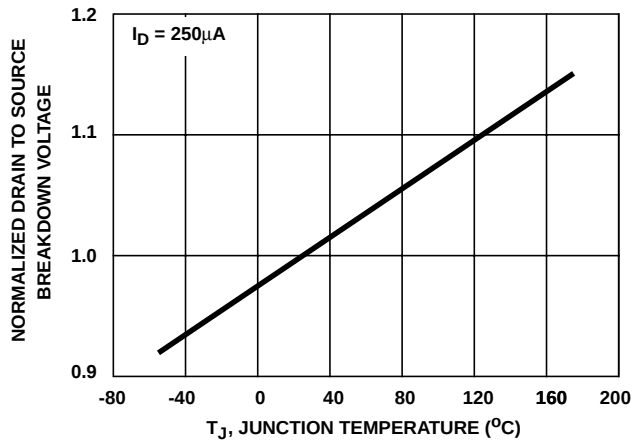


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

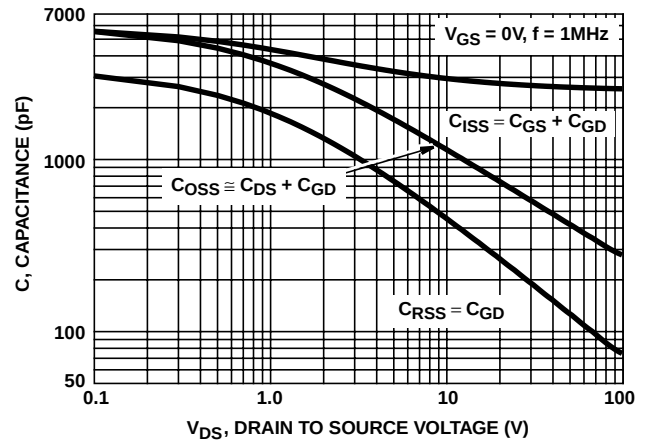
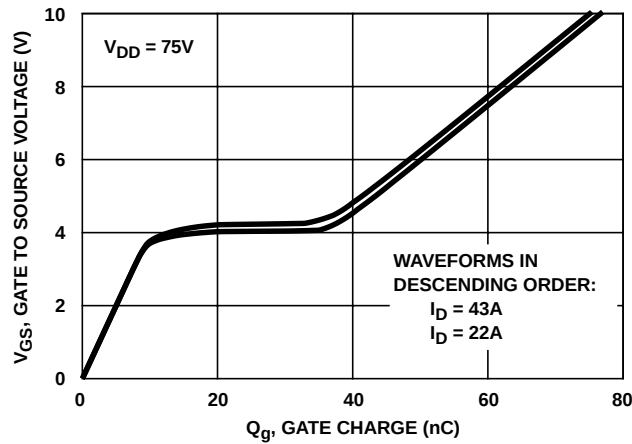


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Intersil Application Notes AN7254 and AN7260.

FIGURE 13. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

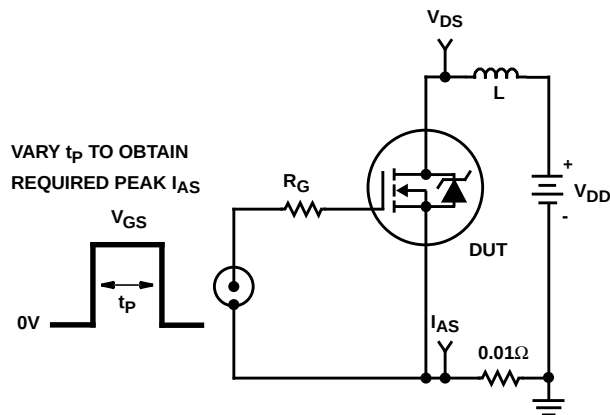


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

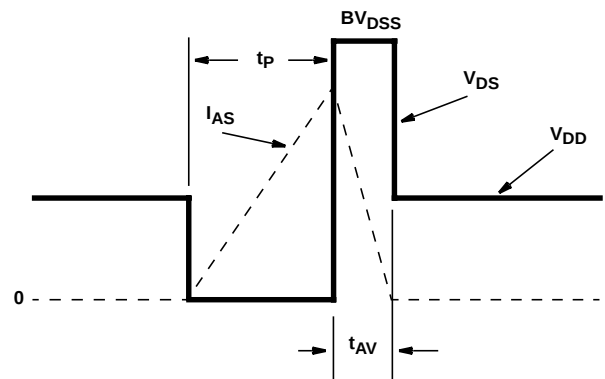


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

Test Circuits and Waveforms (Continued)

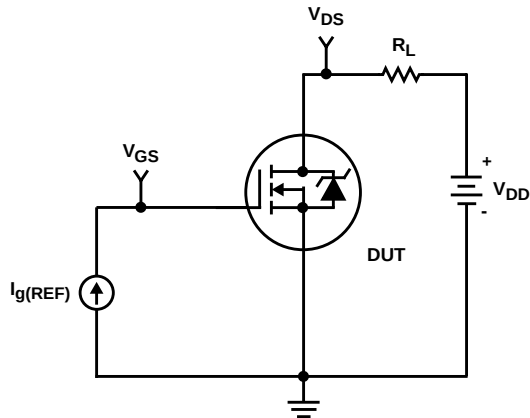


FIGURE 16. GATE CHARGE TEST CIRCUIT

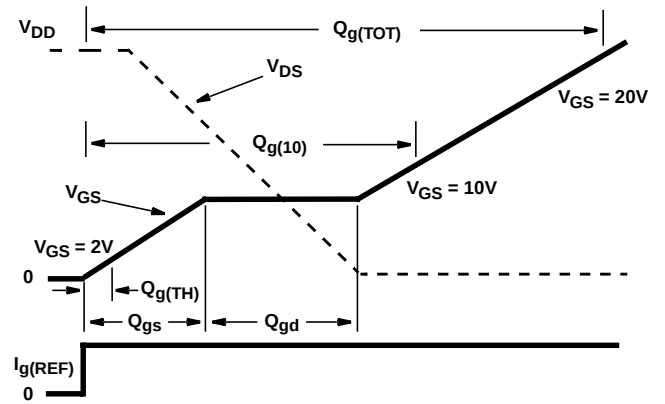


FIGURE 17. GATE CHARGE WAVEFORMS

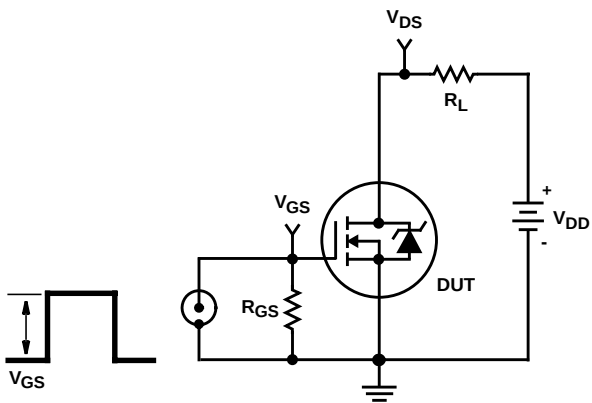


FIGURE 18. SWITCHING TIME TEST CIRCUIT

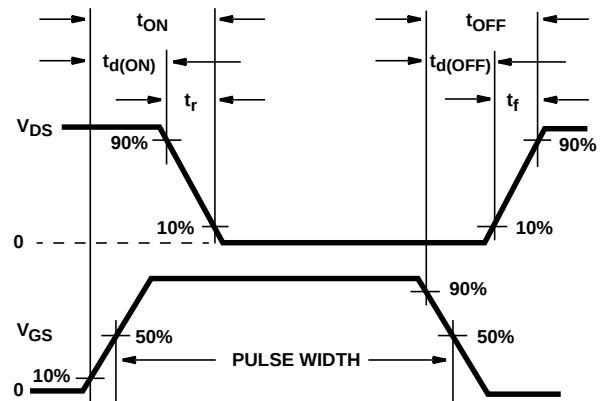


FIGURE 19. SWITCHING TIME WAVEFORM

SPICE Thermal Model

REV 13 October 1999

HUF75842T

CTHERM1 th 6 5.20e-3
CTHERM2 6 5 2.40e-2
CTHERM3 5 4 2.00e-2
CTHERM4 4 3 1.80e-2
CTHERM5 3 2 2.40e-2
CTHERM6 2 tl 1.80e-1

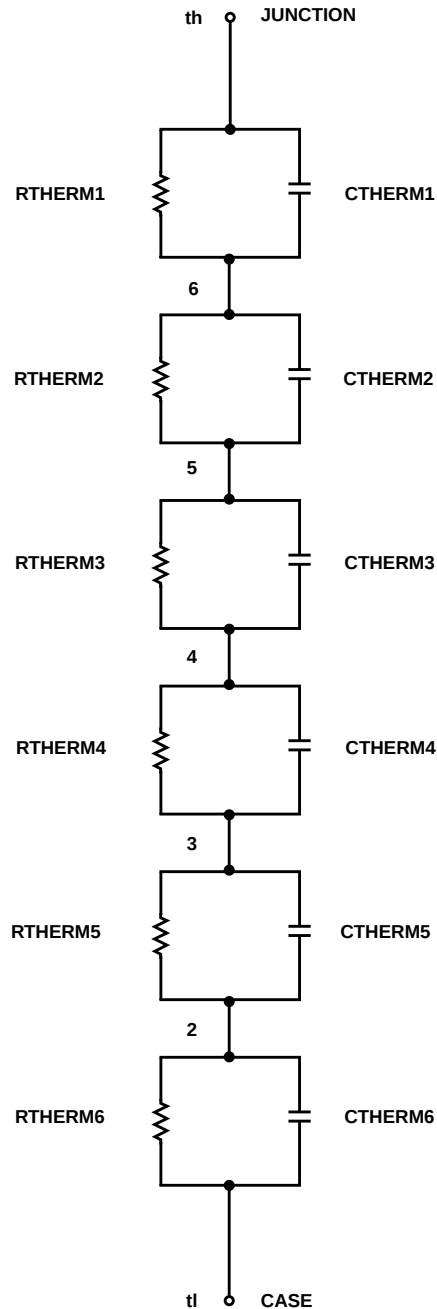
RTHERM1 th 6 1.00e-2
RTHERM2 6 5 2.00e-2
RTHERM3 5 4 6.40e-2
RTHERM4 4 3 1.00e-1
RTHERM5 3 2 1.56e-1
RTHERM6 2 tl 1.65e-1

SABER Thermal Model

SABER thermal model HUF75842T

```
template thermal_model th tl
thermal_c th, tl
{
  ctherm.ctherm1 th 6 = 5.20e-3
  ctherm.ctherm2 6 5 = 2.40e-2
  ctherm.ctherm3 5 4 = 2.00e-2
  ctherm.ctherm4 4 3 = 1.80e-2
  ctherm.ctherm5 3 2 = 2.40e-2
  ctherm.ctherm6 2 tl = 1.80e-1

  rtherm.rtherm1 th 6 = 1.00e-2
  rtherm.rtherm2 6 5 = 2.00e-2
  rtherm.rtherm3 5 4 = 6.40e-2
  rtherm.rtherm4 4 3 = 1.00e-1
  rtherm.rtherm5 3 2 = 1.56e-1
  rtherm.rtherm6 2 tl = 1.65e-1
}
```



All Intersil semiconductor products are manufactured, assembled and tested under **ISO9000** quality systems certification.

Intersil semiconductor products are sold by description only. Intersil Corporation reserves the right to make changes in circuit design and/or specifications at any time without notice. Accordingly, the reader is cautioned to verify that data sheets are current before placing orders. Information furnished by Intersil is believed to be accurate and reliable. However, no responsibility is assumed by Intersil or its subsidiaries for its use; nor for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Intersil or its subsidiaries.

For information regarding Intersil Corporation and its products, see web site www.intersil.com

Sales Office Headquarters

NORTH AMERICA
Intersil Corporation
P. O. Box 883, Mail Stop 53-204
Melbourne, FL 32902
TEL: (321) 724-7143
FAX: (321) 724-7240

EUROPE
Intersil SA
Mercure Center
100, Rue de la Fusee
1130 Brussels, Belgium
TEL: (32) 2.724.2111
FAX: (32) 2.724.22.05

ASIA
Intersil (Taiwan) Ltd.
7F-6, No. 101 Fu Hsing North Road
Taipei, Taiwan
Republic of China
TEL: (886) 2 2716 9310
FAX: (886) 2 2715 3029